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## Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

## Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

### Details

Product Status	Active
Number of LABs/CLBs	264
Number of Logic Elements/Cells	2112
Total RAM Bits	75776
Number of I/O	79
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmx02-2000he-4tg100c">https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmx02-2000he-4tg100c</a>

## Features

### ■ Flexible Logic Architecture

- Six devices with 256 to 6864 LUT4s and 18 to 334 I/Os

### ■ Ultra Low Power Devices

- Advanced 65 nm low power process
- As low as 22  $\mu$ W standby power
- Programmable low swing differential I/Os
- Stand-by mode and other power saving options

### ■ Embedded and Distributed Memory

- Up to 240 kbits sysMEM™ Embedded Block RAM
- Up to 54 kbits Distributed RAM
- Dedicated FIFO control logic

### ■ On-Chip User Flash Memory

- Up to 256 kbits of User Flash Memory
- 100,000 write cycles
- Accessible through WISHBONE, SPI, I<sup>2</sup>C and JTAG interfaces
- Can be used as soft processor PROM or as Flash memory

### ■ Pre-Engineered Source Synchronous I/O

- DDR registers in I/O cells
- Dedicated gearing logic
- 7:1 Gearing for Display I/Os
- Generic DDR, DDRX2, DDRX4
- Dedicated DDR/DDR2/LPDDR memory with DQS support

### ■ High Performance, Flexible I/O Buffer

- Programmable sysIO™ buffer supports wide range of interfaces:
  - LVCMOS 3.3/2.5/1.8/1.5/1.2
  - LVTTTL
  - PCI
  - LVDS, Bus-LVDS, MLVDS, RSDS, LVPECL
  - SSTL 25/18
  - HSTL 18
  - Schmitt trigger inputs, up to 0.5 V hysteresis
- I/Os support hot socketing
- On-chip differential termination
- Programmable pull-up or pull-down mode

### ■ Flexible On-Chip Clocking

- Eight primary clocks
- Up to two edge clocks for high-speed I/O interfaces (top and bottom sides only)
- Up to two analog PLLs per device with fractional-n frequency synthesis
  - Wide input frequency range (7 MHz to 400 MHz)

### ■ Non-volatile, Infinitely Reconfigurable

- Instant-on – powers up in microseconds
- Single-chip, secure solution
- Programmable through JTAG, SPI or I<sup>2</sup>C
- Supports background programming of non-volatile memory
- Optional dual boot with external SPI memory

### ■ TransFR™ Reconfiguration

- In-field logic update while system operates

### ■ Enhanced System Level Support

- On-chip hardened functions: SPI, I<sup>2</sup>C, timer/counter
- On-chip oscillator with 5.5% accuracy
- Unique TraceID for system tracking
- One Time Programmable (OTP) mode
- Single power supply with extended operating range
- IEEE Standard 1149.1 boundary scan
- IEEE 1532 compliant in-system programming

### ■ Broad Range of Package Options

- TQFP, WLCSP, ucBGA, csBGA, caBGA, ftBGA, fpBGA, QFN package options
- Small footprint package options
  - As small as 2.5 mm x 2.5 mm
- Density migration supported
- Advanced halogen-free packaging

**Figure 2-4. Slice Diagram**



For Slices 0 and 1, memory control signals are generated from Slice 2 as follows:

- WCK is CLK
- WRE is from LSR
- DI[3:2] for Slice 1 and DI[1:0] for Slice 0 data from Slice 2
- WAD [A:D] is a 4-bit address from slice 2 LUT input

**Table 2-2. Slice Signal Descriptions**

Function	Type	Signal Names	Description
Input	Data signal	A0, B0, C0, D0	Inputs to LUT4
Input	Data signal	A1, B1, C1, D1	Inputs to LUT4
Input	Multi-purpose	M0/M1	Multi-purpose input
Input	Control signal	CE	Clock enable
Input	Control signal	LSR	Local set/reset
Input	Control signal	CLK	System clock
Input	Inter-PFU signal	FCIN	Fast carry in <sup>1</sup>
Output	Data signals	F0, F1	LUT4 output register bypass signals
Output	Data signals	Q0, Q1	Register outputs
Output	Data signals	OFX0	Output of a LUT5 MUX
Output	Data signals	OFX1	Output of a LUT6, LUT7, LUT8 <sup>2</sup> MUX depending on the slice
Output	Inter-PFU signal	FCO	Fast carry out <sup>1</sup>

1. See Figure 2-3 for connection details.

2. Requires two PFUs.

**Figure 2-6. Secondary High Fanout Nets for MachXO2 Devices**



## sysCLOCK Phase Locked Loops (PLLs)

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The MachXO2-640U, MachXO2-1200/U and larger devices have one or more sysCLOCK PLL. CLKI is the reference frequency input to the PLL and its source can come from an external I/O pin or from internal routing. CLKFB is the feedback signal to the PLL which can come from internal routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

The MachXO2 sysCLOCK PLLs support high resolution (16-bit) fractional-N synthesis. Fractional-N frequency synthesis allows the user to generate an output clock which is a non-integer multiple of the input frequency. For more information about using the PLL with Fractional-N synthesis, please see TN1199, [MachXO2 sysCLOCK PLL Design and Usage Guide](#).

Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The output dividers may also be cascaded together to generate low frequency clocks. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the MachXO2 clock distribution network directly or general purpose routing resources can be used.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected. A block diagram of the PLL is shown in Figure 2-7.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock.

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## DDR Memory Support

Certain PICs on the right edge of MachXO2-640U, MachXO2-1200/U and larger devices, have additional circuitry to allow the implementation of DDR memory interfaces. There are two groups of 14 or 12 PIOs each on the right edge with additional circuitry to implement DDR memory interfaces. This capability allows the implementation of up to 16-bit wide memory interfaces. One PIO from each group contains a control element, the DQS Read/Write Block, to facilitate the generation of clock and control signals (DQSR90, DQSW90, DDRCLKPOL and DATAVALID). These clock and control signals are distributed to the other PIO in the group through dedicated low skew routing.

### DQS Read Write Block

Source synchronous interfaces generally require the input clock to be adjusted in order to correctly capture data at the input register. For most interfaces a PLL is used for this adjustment. However, in DDR memories the clock (referred to as DQS) is not free-running so this approach cannot be used. The DQS Read Write block provides the required clock alignment for DDR memory interfaces. DQSR90 and DQSW90 signals are generated by the DQS Read Write block from the DQS input.

In a typical DDR memory interface design, the phase relationship between the incoming delayed DQS strobe and the internal system clock (during the read cycle) is unknown. The MachXO2 family contains dedicated circuits to transfer data between these domains. To prevent set-up and hold violations, at the domain transfer between DQS (delayed) and the system clock, a clock polarity selector is used. This circuit changes the edge on which the data is registered in the synchronizing registers in the input register block. This requires evaluation at the start of each read cycle for the correct clock polarity. Prior to the read operation in DDR memories, DQS is in tri-state (pulled by termination). The DDR memory device drives DQS low at the start of the preamble state. A dedicated circuit in the DQS Read Write block detects the first DQS rising edge after the preamble state and generates the DDRCLKPOL signal. This signal is used to control the polarity of the clock to the synchronizing registers.

The temperature, voltage and process variations of the DQS delay block are compensated by a set of calibration signals (6-bit bus) from a DLL on the right edge of the device. The DLL loop is compensated for temperature, voltage and process variations by the system clock and feedback loop.

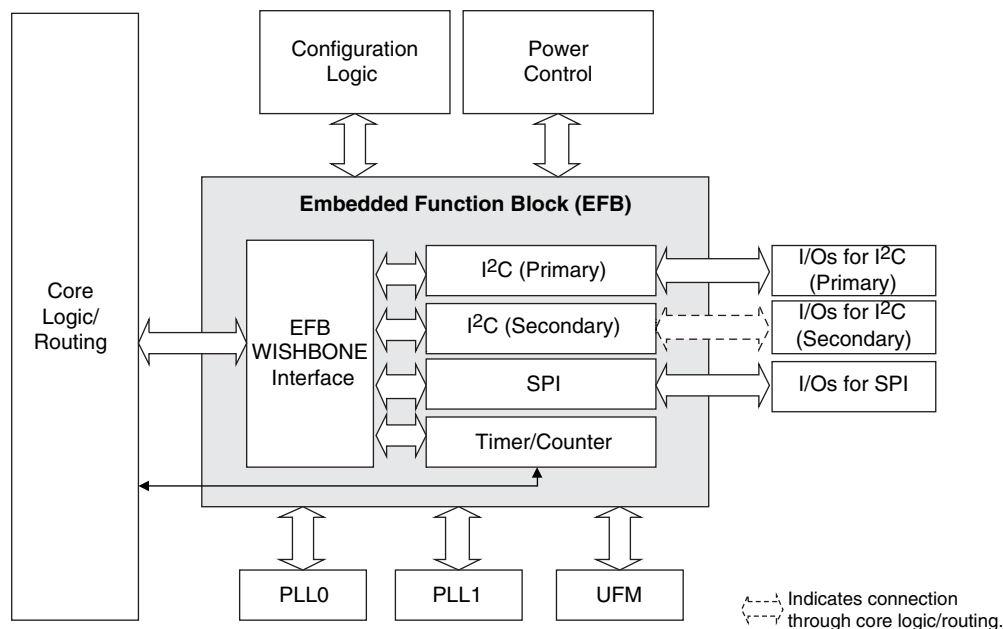
### sysIO Buffer

Each I/O is associated with a flexible buffer referred to as a sysIO buffer. These buffers are arranged around the periphery of the device in groups referred to as banks. The sysIO buffers allow users to implement a wide variety of standards that are found in today's systems including LVCMOS, TTL, PCI, SSTL, HSTL, LVDS, BLVDS, MLVDS and LVPECL.

Each bank is capable of supporting multiple I/O standards. In the MachXO2 devices, single-ended output buffers, ratioed input buffers (LVTTL, LVCMOS and PCI), differential (LVDS) and referenced input buffers (SSTL and HSTL) are powered using I/O supply voltage ( $V_{CCIO}$ ). Each sysIO bank has its own  $V_{CCIO}$ . In addition, each bank has a voltage reference,  $V_{REF}$  which allows the use of referenced input buffers independent of the bank  $V_{CCIO}$ .

MachXO2-256 and MachXO2-640 devices contain single-ended ratioed input buffers and single-ended output buffers with complementary outputs on all the I/O banks. Note that the single-ended input buffers on these devices do not contain PCI clamps. In addition to the single-ended I/O buffers these two devices also have differential and referenced input buffers on all I/Os. The I/Os are arranged in pairs, the two pads in the pair are described as "T" and "C", where the true pad is associated with the positive side of the differential input buffer and the comp (complementary) pad is associated with the negative side of the differential input buffer.

**Figure 2-20. Embedded Function Block Interface**



## Hardened I<sup>2</sup>C IP Core

Every MachXO2 device contains two I<sup>2</sup>C IP cores. These are the primary and secondary I<sup>2</sup>C IP cores. Either of the two cores can be configured either as an I<sup>2</sup>C master or as an I<sup>2</sup>C slave. The only difference between the two IP cores is that the primary core has pre-assigned I/O pins whereas users can assign I/O pins for the secondary core.

When the IP core is configured as a master it will be able to control other devices on the I<sup>2</sup>C bus through the interface. When the core is configured as the slave, the device will be able to provide I/O expansion to an I<sup>2</sup>C Master. The I<sup>2</sup>C cores support the following functionality:

- Master and Slave operation
- 7-bit and 10-bit addressing
- Multi-master arbitration support
- Up to 400 kHz data transfer speed
- General call support
- Interface to custom logic through 8-bit WISHBONE interface

There are some limitations on the use of the hardened user SPI. These are defined in the following technical notes:

- TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) (Appendix B)
- TN1205, [Using User Flash Memory and Hardened Control Functions in MachXO2 Devices](#)

**Figure 2-22. SPI Core Block Diagram**

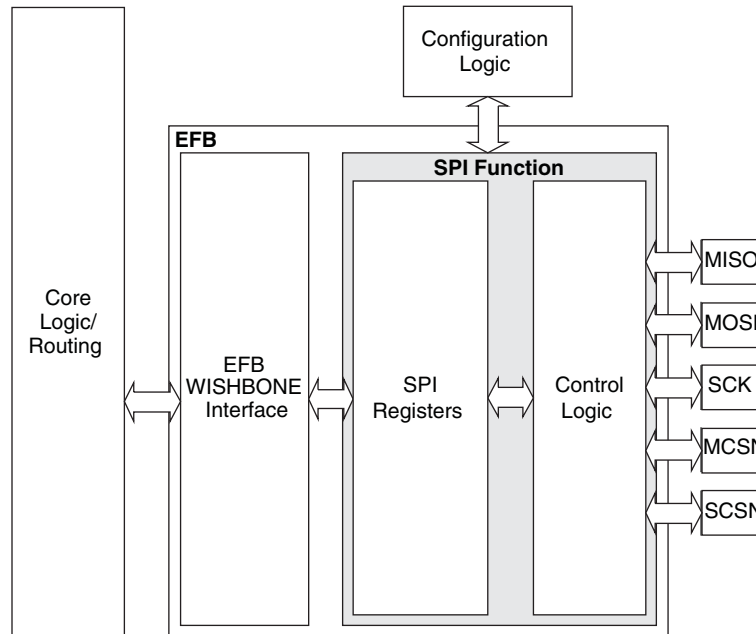


Table 2-16 describes the signals interfacing with the SPI cores.

**Table 2-16. SPI Core Signal Description**

Signal Name	I/O	Master/Slave	Description
spi_csn[0]	O	Master	SPI master chip-select output
spi_csn[1..7]	O	Master	Additional SPI chip-select outputs (total up to eight slaves)
spi_scsn	I	Slave	SPI slave chip-select input
spi_irq	O	Master/Slave	Interrupt request
spi_clk	I/O	Master/Slave	SPI clock. Output in master mode. Input in slave mode.
spi_miso	I/O	Master/Slave	SPI data. Input in master mode. Output in slave mode.
spi_mosi	I/O	Master/Slave	SPI data. Output in master mode. Input in slave mode.
ufm_sn	I	Slave	Configuration Slave Chip Select (active low), dedicated for selecting the User Flash Memory (UFM).
cfg_stdbby	O	Master/Slave	Stand-by signal – To be connected only to the power module of the MachXO2 device. The signal is enabled only if the “Wakeup Enable” feature has been set within the EFB GUI, SPI Tab.
cfg_wake	O	Master/Slave	Wake-up signal – To be connected only to the power module of the MachXO2 device. The signal is enabled only if the “Wakeup Enable” feature has been set within the EFB GUI, SPI Tab.

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## Configuration and Testing

This section describes the configuration and testing features of the MachXO2 family.

### IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO2 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with  $V_{CCIO}$  Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#) and TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#).

### Device Configuration

All MachXO2 devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I<sup>2</sup>C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO2 device:

1. Internal Flash Download
2. JTAG
3. Standard Serial Peripheral Interface (Master SPI mode) – interface to boot PROM memory
4. System microprocessor to drive a serial slave SPI port (SSPI mode)
5. Standard I<sup>2</sup>C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1204, [MachXO2 Programming and Configuration Usage Guide](#) for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO2 devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip Flash memory, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip Flash memory. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) for details.



When implementing background programming of the on-chip Flash, care must be taken for the operation of the PLL. For devices that have two PLLs (XO2-2000U, -4000 and -7000), the system must put the RPLL (Right-side PLL) in reset state during the background Flash programming. More detailed description can be found in TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### **Security and One-Time Programmable Mode (OTP)**

For applications where security is important, the lack of an external bitstream provides a solution that is inherently more secure than SRAM-based FPGAs. This is further enhanced by device locking. MachXO2 devices contain security bits that, when set, prevent the readback of the SRAM configuration and non-volatile Flash memory spaces. The device can be in one of two modes:

1. Unlocked – Readback of the SRAM configuration and non-volatile Flash memory spaces is allowed.
2. Permanently Locked – The device is permanently locked.

Once set, the only way to clear the security bits is to erase the device. To further complement the security of the device, a One Time Programmable (OTP) mode is available. Once the device is set in this mode it is not possible to erase or re-program the Flash and SRAM OTP portions of the device. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### **Dual Boot**

MachXO2 devices can optionally boot from two patterns, a primary bitstream and a golden bitstream. If the primary bitstream is found to be corrupt while being downloaded into the SRAM, the device shall then automatically re-boot from the golden bitstream. Note that the primary bitstream must reside in the on-chip Flash. The golden image MUST reside in an external SPI Flash. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### **Soft Error Detection**

The SED feature is a CRC check of the SRAM cells after the device is configured. This check ensures that the SRAM cells were configured successfully. This feature is enabled by a configuration bit option. The Soft Error Detection can also be initiated in user mode via an input to the fabric. The clock for the Soft Error Detection circuit is generated using a dedicated divider. The undivided clock from the on-chip oscillator is the input to this divider. For low power applications users can switch off the Soft Error Detection circuit. For more details, refer to TN1206, [MachXO2 Soft Error Detection Usage Guide](#).

### **TraceID**

Each MachXO2 device contains a unique (per device), TraceID that can be used for tracking purposes or for IP security applications. The TraceID is 64 bits long. Eight out of 64 bits are user-programmable, the remaining 56 bits are factory-programmed. The TraceID is accessible through the EFB WISHBONE interface and can also be accessed through the SPI, I<sup>2</sup>C, or JTAG interfaces.

### **Density Shifting**

The MachXO2 family has been designed to enable density migration within the same package. Furthermore, the architecture ensures a high success rate when performing design migration from lower density devices to higher density devices. In many cases, it is also possible to shift a lower utilization design targeted for a high-density device to a lower density device. However, the exact details of the final resource utilization will impact the likely success in each case. When migrating from lower to higher density or higher to lower density, ensure to review all the power supplies and NC pins of the chosen devices. For more details refer to the [MachXO2 migration files](#).

**sysIO Single-Ended DC Electrical Characteristics<sup>1, 2</sup>**

Input/Output Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$ Max. (V)	$V_{OH}$ Min. (V)	$I_{OL}$ Max. <sup>4</sup> (mA)	$I_{OH}$ Max. <sup>4</sup> (mA)
	Min. (V) <sup>3</sup>	Max. (V)	Min. (V)	Max. (V)				
LVCMOS 3.3 LVTTL	-0.3	0.8	2.0	3.6	0.4	$V_{CCIO} - 0.4$	4	-4
							8	-8
							12	-12
							16	-16
							24	-24
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
LVCMOS 2.5	-0.3	0.7	1.7	3.6	0.4	$V_{CCIO} - 0.4$	4	-4
							8	-8
							12	-12
							16	-16
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
LVCMOS 1.8	-0.3	$0.35V_{CCIO}$	$0.65V_{CCIO}$	3.6	0.4	$V_{CCIO} - 0.4$	4	-4
							8	-8
							12	-12
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
LVCMOS 1.5	-0.3	$0.35V_{CCIO}$	$0.65V_{CCIO}$	3.6	0.4	$V_{CCIO} - 0.4$	4	-4
					0.2	$V_{CCIO} - 0.2$	8	-8
							12	-12
LVCMOS 1.2	-0.3	$0.35V_{CCIO}$	$0.65V_{CCIO}$	3.6	0.4	$V_{CCIO} - 0.4$	4	-2
							8	-6
							0.1	-0.1
					0.2	$V_{CCIO} - 0.2$	0.1	-0.1
PCI	-0.3	$0.3V_{CCIO}$	$0.5V_{CCIO}$	3.6	$0.1V_{CCIO}$	$0.9V_{CCIO}$	1.5	-0.5
SSTL25 Class I	-0.3	$V_{REF} - 0.18$	$V_{REF} + 0.18$	3.6	0.54	$V_{CCIO} - 0.62$	8	8
SSTL25 Class II	-0.3	$V_{REF} - 0.18$	$V_{REF} + 0.18$	3.6	NA	NA	NA	NA
SSTL18 Class I	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	3.6	0.40	$V_{CCIO} - 0.40$	8	8
SSTL18 Class II	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	3.6	NA	NA	NA	NA
HSTL18 Class I	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	$V_{CCIO} - 0.40$	8	8
HSTL18 Class II	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS25R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS18R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS18R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS15R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS15R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	NA	NA	NA	NA
LVCMOS12R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	24, 16, 12, 8, 4	NA Open Drain
LVCMOS12R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	16, 12, 8, 4	NA Open Drain
LVCMOS10R33	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	24, 16, 12, 8, 4	NA Open Drain

Input/Output Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$ Max. (V)	$V_{OH}$ Min. (V)	$I_{OL}$ Max. <sup>4</sup> (mA)	$I_{OH}$ Max. <sup>4</sup> (mA)
	Min. (V) <sup>3</sup>	Max. (V)	Min. (V)	Max. (V)				
LVC MOS10R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	16, 12, 8, 4	NA Open Drain

1. MachXO2 devices allow LVC MOS inputs to be placed in I/O banks where  $V_{CCIO}$  is different from what is specified in the applicable JEDEC specification. This is referred to as a ratioed input buffer. In a majority of cases this operation follows or exceeds the applicable JEDEC specification. The cases where MachXO2 devices do not meet the relevant JEDEC specification are documented in the table below.
2. MachXO2 devices allow for LVC MOS referenced I/Os which follow applicable JEDEC specifications. For more details about mixed mode operation please refer to please refer to TN1202, [MachXO2 sysIO Usage Guide](#).
3. The dual function I<sup>2</sup>C pins SCL and SDA are limited to a  $V_{IL}$  min of -0.25 V or to -0.3 V with a duration of <10 ns.
4. For electromigration, the average DC current sourced or sinked by I/O pads between two consecutive  $V_{CCIO}$  or GND pad connections, or between the last  $V_{CCIO}$  or GND in an I/O bank and the end of an I/O bank, as shown in the Logic Signal Connections table (also shown as I/O grouping) shall not exceed a maximum of  $n * 8$  mA. "n" is the number of I/O pads between the two consecutive bank  $V_{CCIO}$  or GND connections or between the last  $V_{CCIO}$  and GND in a bank and the end of a bank. IO Grouping can be found in the Data Sheet Pin Tables, which can also be generated from the Lattice Diamond software.

Input Standard	$V_{CCIO}$ (V)	$V_{IL}$ Max. (V)
LVC MOS 33	1.5	0.685
LVC MOS 25	1.5	0.687
LVC MOS 18	1.5	0.655

## sysIO Differential Electrical Characteristics

The LVDS differential output buffers are available on the top side of MachXO2-640U, MachXO2-1200/U and higher density devices in the MachXO2 PLD family.

### LVDS

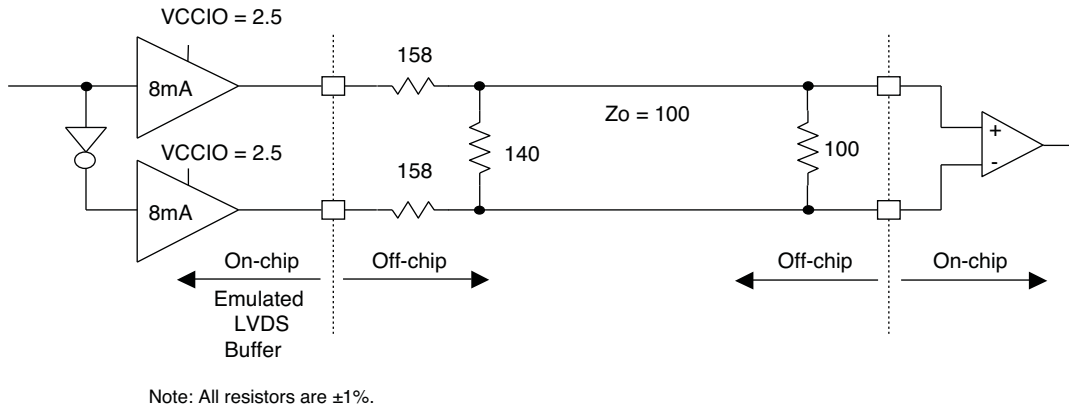
#### Over Recommended Operating Conditions

Parameter Symbol	Parameter Description	Test Conditions	Min.	Typ.	Max.	Units
$V_{INP}$ $V_{INM}$	Input Voltage	$V_{CCIO} = 3.3$ V	0	—	2.605	V
		$V_{CCIO} = 2.5$ V	0	—	2.05	V
$V_{THD}$	Differential Input Threshold		±100	—		mV
$V_{CM}$	Input Common Mode Voltage	$V_{CCIO} = 3.3$ V	0.05	—	2.6	V
		$V_{CCIO} = 2.5$ V	0.05	—	2.0	V
$I_{IN}$	Input current	Power on	—	—	±10	μA
$V_{OH}$	Output high voltage for $V_{OP}$ or $V_{OM}$	$R_T = 100$ Ohm	—	1.375	—	V
$V_{OL}$	Output low voltage for $V_{OP}$ or $V_{OM}$	$R_T = 100$ Ohm	0.90	1.025	—	V
$V_{OD}$	Output voltage differential	$(V_{OP} - V_{OM})$ , $R_T = 100$ Ohm	250	350	450	mV
$\Delta V_{OD}$	Change in $V_{OD}$ between high and low		—	—	50	mV
$V_{OS}$	Output voltage offset	$(V_{OP} + V_{OM})/2$ , $R_T = 100$ Ohm	1.125	1.20	1.395	V
$\Delta V_{OS}$	Change in $V_{OS}$ between H and L		—	—	50	mV
$I_{OSD}$	Output short circuit current	$V_{OD} = 0$ V driver outputs shorted	—	—	24	mA

### LVDS Emulation

MachXO2 devices can support LVDS outputs via emulation (LVDS25E). The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs on all devices. The scheme shown in Figure 3-1 is one possible solution for LVDS standard implementation. Resistor values in Figure 3-1 are industry standard values for 1% resistors.

**Figure 3-1. LVDS Using External Resistors (LVDS25E)**



**Table 3-1. LVDS25E DC Conditions**

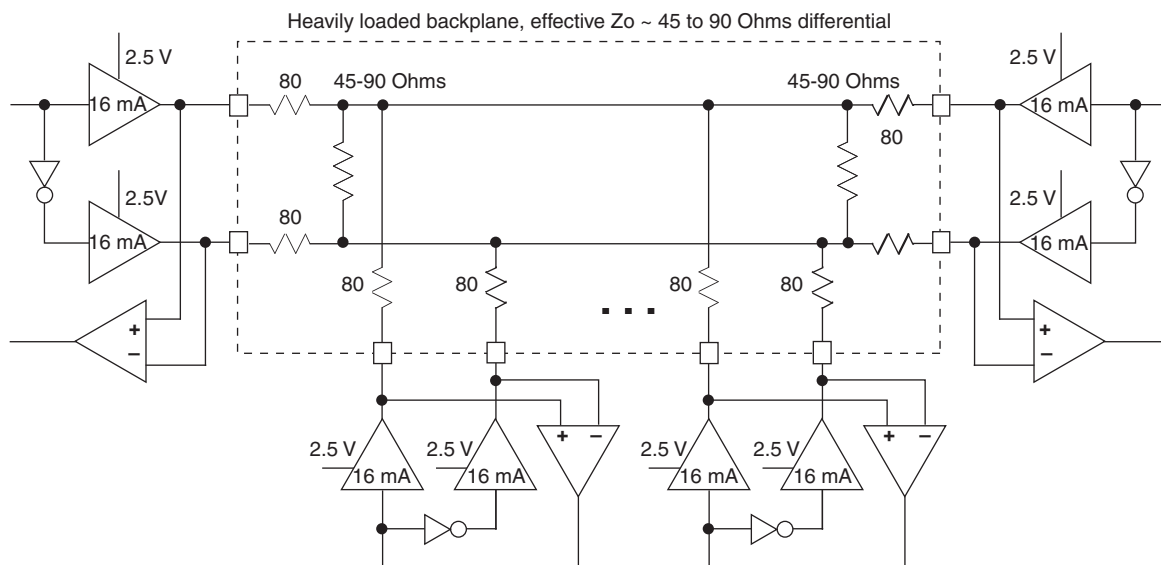
#### Over Recommended Operating Conditions

Parameter	Description	Typ.	Units
$Z_{OUT}$	Output impedance	20	Ohms
$R_S$	Driver series resistor	158	Ohms
$R_P$	Driver parallel resistor	140	Ohms
$R_T$	Receiver termination	100	Ohms
$V_{OH}$	Output high voltage	1.43	V
$V_{OL}$	Output low voltage	1.07	V
$V_{OD}$	Output differential voltage	0.35	V
$V_{CM}$	Output common mode voltage	1.25	V
$Z_{BACK}$	Back impedance	100.5	Ohms
$I_{DC}$	DC output current	6.03	mA

### BLVDS

The MachXO2 family supports the BLVDS standard through emulation. The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs. The input standard is supported by the LVDS differential input buffer. BLVDS is intended for use when multi-drop and bi-directional multi-point differential signaling is required. The scheme shown in Figure 3-2 is one possible solution for bi-directional multi-point differential signals.

**Figure 3-2. BLVDS Multi-point Output Example**



**Table 3-2. BLVDS DC Conditions<sup>1</sup>**

#### Over Recommended Operating Conditions

Symbol	Description	Nominal		Units
		Zo = 45	Zo = 90	
Z <sub>OUT</sub>	Output impedance	20	20	Ohms
R <sub>S</sub>	Driver series resistance	80	80	Ohms
R <sub>TLEFT</sub>	Left end termination	45	90	Ohms
R <sub>TRIGHT</sub>	Right end termination	45	90	Ohms
V <sub>OH</sub>	Output high voltage	1.376	1.480	V
V <sub>OL</sub>	Output low voltage	1.124	1.020	V
V <sub>OD</sub>	Output differential voltage	0.253	0.459	V
V <sub>CM</sub>	Output common mode voltage	1.250	1.250	V
I <sub>DC</sub>	DC output current	11.236	10.204	mA

1. For input buffer, see LVDS table.

### MachXO2 External Switching Characteristics – HC/HE Devices<sup>1, 2, 3, 4, 5, 6, 7</sup>

Over Recommended Operating Conditions

Parameter	Description	Device	–6		–5		–4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Clocks									
Primary Clocks									
f <sub>MAX_PRI</sub> <sup>8</sup>	Frequency for Primary Clock Tree	All MachXO2 devices	—	388	—	323	—	269	MHz
t <sub>W_PRI</sub>	Clock Pulse Width for Primary Clock	All MachXO2 devices	0.5	—	0.6	—	0.7	—	ns
t <sub>SKEW_PRI</sub>	Primary Clock Skew Within a Device	MachXO2-256HC-HE	—	912	—	939	—	975	ps
		MachXO2-640HC-HE	—	844	—	871	—	908	ps
		MachXO2-1200HC-HE	—	868	—	902	—	951	ps
		MachXO2-2000HC-HE	—	867	—	897	—	941	ps
		MachXO2-4000HC-HE	—	865	—	892	—	931	ps
		MachXO2-7000HC-HE	—	902	—	942	—	989	ps
Edge Clock									
f <sub>MAX_EDGE</sub> <sup>8</sup>	Frequency for Edge Clock	MachXO2-1200 and larger devices	—	400	—	333	—	278	MHz
Pin-LUT-Pin Propagation Delay									
t <sub>PD</sub>	Best case propagation delay through one LUT-4	All MachXO2 devices	—	6.72	—	6.96	—	7.24	ns
General I/O Pin Parameters (Using Primary Clock without PLL)									
t <sub>CO</sub>	Clock to Output – PIO Output Register	MachXO2-256HC-HE	—	7.13	—	7.30	—	7.57	ns
		MachXO2-640HC-HE	—	7.15	—	7.30	—	7.57	ns
		MachXO2-1200HC-HE	—	7.44	—	7.64	—	7.94	ns
		MachXO2-2000HC-HE	—	7.46	—	7.66	—	7.96	ns
		MachXO2-4000HC-HE	—	7.51	—	7.71	—	8.01	ns
		MachXO2-7000HC-HE	—	7.54	—	7.75	—	8.06	ns
t <sub>SU</sub>	Clock to Data Setup – PIO Input Register	MachXO2-256HC-HE	–0.06	—	–0.06	—	–0.06	—	ns
		MachXO2-640HC-HE	–0.06	—	–0.06	—	–0.06	—	ns
		MachXO2-1200HC-HE	–0.17	—	–0.17	—	–0.17	—	ns
		MachXO2-2000HC-HE	–0.20	—	–0.20	—	–0.20	—	ns
		MachXO2-4000HC-HE	–0.23	—	–0.23	—	–0.23	—	ns
		MachXO2-7000HC-HE	–0.23	—	–0.23	—	–0.23	—	ns
t <sub>H</sub>	Clock to Data Hold – PIO Input Register	MachXO2-256HC-HE	1.75	—	1.95	—	2.16	—	ns
		MachXO2-640HC-HE	1.75	—	1.95	—	2.16	—	ns
		MachXO2-1200HC-HE	1.88	—	2.12	—	2.36	—	ns
		MachXO2-2000HC-HE	1.89	—	2.13	—	2.37	—	ns
		MachXO2-4000HC-HE	1.94	—	2.18	—	2.43	—	ns
		MachXO2-7000HC-HE	1.98	—	2.23	—	2.49	—	ns

### I<sup>2</sup>C Port Timing Specifications<sup>1, 2</sup>

Symbol	Parameter	Min.	Max.	Units
f <sub>MAX</sub>	Maximum SCL clock frequency	—	400	kHz

- MachXO2 supports the following modes:
  - Standard-mode (Sm), with a bit rate up to 100 kbit/s (user and configuration mode)
  - Fast-mode (Fm), with a bit rate up to 400 kbit/s (user and configuration mode)
- Refer to the I<sup>2</sup>C specification for timing requirements.

### SPI Port Timing Specifications<sup>1</sup>

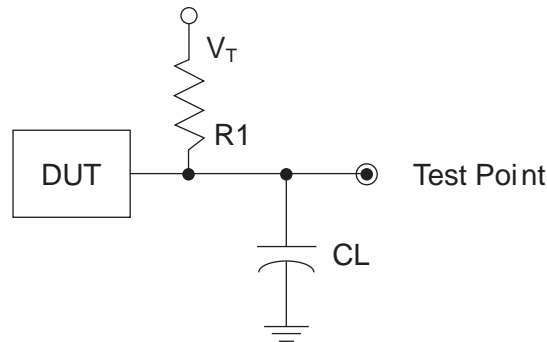
Symbol	Parameter	Min.	Max.	Units
f <sub>MAX</sub>	Maximum SCK clock frequency	—	45	MHz

- Applies to user mode only. For configuration mode timing specifications, refer to sysCONFIG Port Timing Specifications table in this data sheet.

### Switching Test Conditions

Figure 3-13 shows the output test load used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are shown in Table 3-5.

**Figure 3-13. Output Test Load, LVTTTL and LVCMOS Standards**



**Table 3-5. Test Fixture Required Components, Non-Terminated Interfaces**

Test Condition	R1	CL	Timing Ref.	VT
LVTTTL and LVCMOS settings (L -> H, H -> L)	$\infty$	0pF	LVTTTL, LVCMOS 3.3 = 1.5 V	—
			LVCMOS 2.5 = V <sub>CCIO</sub> /2	—
			LVCMOS 1.8 = V <sub>CCIO</sub> /2	—
			LVCMOS 1.5 = V <sub>CCIO</sub> /2	—
			LVCMOS 1.2 = V <sub>CCIO</sub> /2	—
LVTTTL and LVCMOS 3.3 (Z -> H)	188	0pF	1.5 V	V <sub>OL</sub>
LVTTTL and LVCMOS 3.3 (Z -> L)			1.5 V	V <sub>OH</sub>
Other LVCMOS (Z -> H)			V <sub>CCIO</sub> /2	V <sub>OL</sub>
Other LVCMOS (Z -> L)			V <sub>CCIO</sub> /2	V <sub>OH</sub>
LVTTTL + LVCMOS (H -> Z)			V <sub>OH</sub> - 0.15 V	V <sub>OL</sub>
LVTTTL + LVCMOS (L -> Z)			V <sub>OL</sub> - 0.15 V	V <sub>OH</sub>

Note: Output test conditions for all other interfaces are determined by the respective standards.

### Signal Descriptions

Signal Name	I/O	Descriptions
<b>General Purpose</b>		
P[Edge] [Row/Column Number]_[A/B/C/D]	I/O	<p>[Edge] indicates the edge of the device on which the pad is located. Valid edge designations are L (Left), B (Bottom), R (Right), T (Top).</p> <p>[Row/Column Number] indicates the PFU row or the column of the device on which the PIO Group exists. When Edge is T (Top) or (Bottom), only need to specify Row Number. When Edge is L (Left) or R (Right), only need to specify Column Number.</p> <p>[A/B/C/D] indicates the PIO within the group to which the pad is connected.</p> <p>Some of these user-programmable pins are shared with special function pins. When not used as special function pins, these pins can be programmed as I/Os for user logic.</p> <p>During configuration of the user-programmable I/Os, the user has an option to tri-state the I/Os and enable an internal pull-up, pull-down or buskeeper resistor. This option also applies to unused pins (or those not bonded to a package pin). The default during configuration is for user-programmable I/Os to be tri-stated with an internal pull-down resistor enabled. When the device is erased, I/Os will be tri-stated with an internal pull-down resistor enabled. Some pins, such as PROGRAMN and JTAG pins, default to tri-stated I/Os with pull-up resistors enabled when the device is erased.</p>
NC	—	No connect.
GND	—	GND – Ground. Dedicated pins. It is recommended that all GNDs are tied together. For QFN 48 package, the exposed die pad is the device ground.
VCC	—	VCC – The power supply pins for core logic. Dedicated pins. It is recommended that all VCCs are tied to the same supply.
VCCIOx	—	VCCIO – The power supply pins for I/O Bank x. Dedicated pins. It is recommended that all VCCIOs located in the same bank are tied to the same supply.
<b>PLL and Clock Functions</b> (Used as user-programmable I/O pins when not used for PLL or clock pins)		
[LOC]_GPLL[T, C]_IN	—	Reference Clock (PLL) input pads: [LOC] indicates location. Valid designations are L (Left PLL) and R (Right PLL). T = true and C = complement.
[LOC]_GPLL[T, C]_FB	—	Optional Feedback (PLL) input pads: [LOC] indicates location. Valid designations are L (Left PLL) and R (Right PLL). T = true and C = complement.
PCLK [n]_[2:0]	—	Primary Clock pads. One to three clock pads per side.
<b>Test and Programming</b> (Dual function pins used for test access port and during sysCONFIG™)		
TMS	I	Test Mode Select input pin, used to control the 1149.1 state machine.
TCK	I	Test Clock input pin, used to clock the 1149.1 state machine.
TDI	I	Test Data input pin, used to load data into the device using an 1149.1 state machine.
TDO	O	Output pin – Test Data output pin used to shift data out of the device using 1149.1.
JTAGENB	I	<p>Optionally controls behavior of TDI, TDO, TMS, TCK. If the device is configured to use the JTAG pins (TDI, TDO, TMS, TCK) as general purpose I/O, then:</p> <p>If JTAGENB is low: TDI, TDO, TMS and TCK can function a general purpose I/O.</p> <p>If JTAGENB is high: TDI, TDO, TMS and TCK function as JTAG pins.</p> <p>For more details, refer to TN1204, <a href="#">MachXO2 Programming and Configuration Usage Guide</a>.</p>
<b>Configuration</b> (Dual function pins used during sysCONFIG)		
PROGRAMN	I	Initiates configuration sequence when asserted low. During configuration, or when reserved as PROGRAMN in user mode, this pin always has an active pull-up.



## Signal Descriptions (Cont.)

Signal Name	I/O	Descriptions
INITN	I/O	Open Drain pin. Indicates the FPGA is ready to be configured. During configuration, or when reserved as INITn in user mode, this pin has an active pull-up.
DONE	I/O	Open Drain pin. Indicates that the configuration sequence is complete, and the start-up sequence is in progress. During configuration, or when reserved as DONE in user mode, this pin has an active pull-up.
MCLK/CCLK	I/O	Input Configuration Clock for configuring an FPGA in Slave SPI mode. Output Configuration Clock for configuring an FPGA in SPI and SPIm configuration modes.
SN	I	Slave SPI active low chip select input.
CSSPIN	I/O	Master SPI active low chip select output.
SI/SPISI	I/O	Slave SPI serial data input and master SPI serial data output.
SO/SPISO	I/O	Slave SPI serial data output and master SPI serial data input.
SCL	I/O	Slave I <sup>2</sup> C clock input and master I <sup>2</sup> C clock output.
SDA	I/O	Slave I <sup>2</sup> C data input and master I <sup>2</sup> C data output.

## **For Further Information**

For further information regarding logic signal connections for various packages please refer to the MachXO2 Device Pinout Files.

## **Thermal Management**

Thermal management is recommended as part of any sound FPGA design methodology. To assess the thermal characteristics of a system, Lattice specifies a maximum allowable junction temperature in all device data sheets. Users must complete a thermal analysis of their specific design to ensure that the device and package do not exceed the junction temperature limits. Refer to the Thermal Management document to find the device/package specific thermal values.

## **For Further Information**

For further information regarding Thermal Management, refer to the following:

- [Thermal Management](#) document
- TN1198, [Power Estimation and Management for MachXO2 Devices](#)
- The Power Calculator tool is included with the Lattice design tools, or as a standalone download from [www.latticesemi.com/software](http://www.latticesemi.com/software)

### Ultra Low Power Commercial Grade Devices, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-256ZE-1SG32C	256	1.2 V	–1	Halogen-Free QFN	32	COM
LCMXO2-256ZE-2SG32C	256	1.2 V	–2	Halogen-Free QFN	32	COM
LCMXO2-256ZE-3SG32C	256	1.2 V	–3	Halogen-Free QFN	32	COM
LCMXO2-256ZE-1UMG64C	256	1.2 V	–1	Halogen-Free ucBGA	64	COM
LCMXO2-256ZE-2UMG64C	256	1.2 V	–2	Halogen-Free ucBGA	64	COM
LCMXO2-256ZE-3UMG64C	256	1.2 V	–3	Halogen-Free ucBGA	64	COM
LCMXO2-256ZE-1TG100C	256	1.2 V	–1	Halogen-Free TQFP	100	COM
LCMXO2-256ZE-2TG100C	256	1.2 V	–2	Halogen-Free TQFP	100	COM
LCMXO2-256ZE-3TG100C	256	1.2 V	–3	Halogen-Free TQFP	100	COM
LCMXO2-256ZE-1MG132C	256	1.2 V	–1	Halogen-Free csBGA	132	COM
LCMXO2-256ZE-2MG132C	256	1.2 V	–2	Halogen-Free csBGA	132	COM
LCMXO2-256ZE-3MG132C	256	1.2 V	–3	Halogen-Free csBGA	132	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-640ZE-1TG100C	640	1.2 V	–1	Halogen-Free TQFP	100	COM
LCMXO2-640ZE-2TG100C	640	1.2 V	–2	Halogen-Free TQFP	100	COM
LCMXO2-640ZE-3TG100C	640	1.2 V	–3	Halogen-Free TQFP	100	COM
LCMXO2-640ZE-1MG132C	640	1.2 V	–1	Halogen-Free csBGA	132	COM
LCMXO2-640ZE-2MG132C	640	1.2 V	–2	Halogen-Free csBGA	132	COM
LCMXO2-640ZE-3MG132C	640	1.2 V	–3	Halogen-Free csBGA	132	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200ZE-1SG32C	1280	1.2 V	–1	Halogen-Free QFN	32	COM
LCMXO2-1200ZE-2SG32C	1280	1.2 V	–2	Halogen-Free QFN	32	COM
LCMXO2-1200ZE-3SG32C	1280	1.2 V	–3	Halogen-Free QFN	32	COM
LCMXO2-1200ZE-1TG100C	1280	1.2 V	–1	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-2TG100C	1280	1.2 V	–2	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-3TG100C	1280	1.2 V	–3	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-1MG132C	1280	1.2 V	–1	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-2MG132C	1280	1.2 V	–2	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-3MG132C	1280	1.2 V	–3	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-1TG144C	1280	1.2 V	–1	Halogen-Free TQFP	144	COM
LCMXO2-1200ZE-2TG144C	1280	1.2 V	–2	Halogen-Free TQFP	144	COM
LCMXO2-1200ZE-3TG144C	1280	1.2 V	–3	Halogen-Free TQFP	144	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000HE-6BG332C	4320	1.2 V	–6	Halogen-Free caBGA	332	COM
LCMXO2-4000HE-4FG484C	4320	1.2 V	–4	Halogen-Free fpBGA	484	COM
LCMXO2-4000HE-5FG484C	4320	1.2 V	–5	Halogen-Free fpBGA	484	COM
LCMXO2-4000HE-6FG484C	4320	1.2 V	–6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000HE-4TG144C	6864	1.2 V	–4	Halogen-Free TQFP	144	COM
LCMXO2-7000HE-5TG144C	6864	1.2 V	–5	Halogen-Free TQFP	144	COM
LCMXO2-7000HE-6TG144C	6864	1.2 V	–6	Halogen-Free TQFP	144	COM
LCMXO2-7000HE-4BG256C	6864	1.2 V	–4	Halogen-Free caBGA	256	COM
LCMXO2-7000HE-5BG256C	6864	1.2 V	–5	Halogen-Free caBGA	256	COM
LCMXO2-7000HE-6BG256C	6864	1.2 V	–6	Halogen-Free caBGA	256	COM
LCMXO2-7000HE-4FTG256C	6864	1.2 V	–4	Halogen-Free ftBGA	256	COM
LCMXO2-7000HE-5FTG256C	6864	1.2 V	–5	Halogen-Free ftBGA	256	COM
LCMXO2-7000HE-6FTG256C	6864	1.2 V	–6	Halogen-Free ftBGA	256	COM
LCMXO2-7000HE-4BG332C	6864	1.2 V	–4	Halogen-Free caBGA	332	COM
LCMXO2-7000HE-5BG332C	6864	1.2 V	–5	Halogen-Free caBGA	332	COM
LCMXO2-7000HE-6BG332C	6864	1.2 V	–6	Halogen-Free caBGA	332	COM
LCMXO2-7000HE-4FG484C	6864	1.2 V	–4	Halogen-Free fpBGA	484	COM
LCMXO2-7000HE-5FG484C	6864	1.2 V	–5	Halogen-Free fpBGA	484	COM
LCMXO2-7000HE-6FG484C	6864	1.2 V	–6	Halogen-Free fpBGA	484	COM

**High-Performance Industrial Grade Devices with Voltage Regulator, Halogen Free (RoHS) Packaging**

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-256HC-4SG32I	256	2.5 V / 3.3 V	–4	Halogen-Free QFN	32	IND
LCMXO2-256HC-5SG32I	256	2.5 V / 3.3 V	–5	Halogen-Free QFN	32	IND
LCMXO2-256HC-6SG32I	256	2.5 V / 3.3 V	–6	Halogen-Free QFN	32	IND
LCMXO2-256HC-4SG48I	256	2.5 V / 3.3 V	–4	Halogen-Free QFN	48	IND
LCMXO2-256HC-5SG48I	256	2.5 V / 3.3 V	–5	Halogen-Free QFN	48	IND
LCMXO2-256HC-6SG48I	256	2.5 V / 3.3 V	–6	Halogen-Free QFN	48	IND
LCMXO2-256HC-4UMG64I	256	2.5 V / 3.3 V	–4	Halogen-Free ucBGA	64	IND
LCMXO2-256HC-5UMG64I	256	2.5 V / 3.3 V	–5	Halogen-Free ucBGA	64	IND
LCMXO2-256HC-6UMG64I	256	2.5 V / 3.3 V	–6	Halogen-Free ucBGA	64	IND
LCMXO2-256HC-4TG100I	256	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	IND
LCMXO2-256HC-5TG100I	256	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	IND
LCMXO2-256HC-6TG100I	256	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	IND
LCMXO2-256HC-4MG132I	256	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-256HC-5MG132I	256	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-256HC-6MG132I	256	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-640HC-4SG48I	640	2.5 V / 3.3 V	–4	Halogen-Free QFN	48	IND
LCMXO2-640HC-5SG48I	640	2.5 V / 3.3 V	–5	Halogen-Free QFN	48	IND
LCMXO2-640HC-6SG48I	640	2.5 V / 3.3 V	–6	Halogen-Free QFN	48	IND
LCMXO2-640HC-4TG100I	640	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	IND
LCMXO2-640HC-5TG100I	640	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	IND
LCMXO2-640HC-6TG100I	640	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	IND
LCMXO2-640HC-4MG132I	640	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-640HC-5MG132I	640	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-640HC-6MG132I	640	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-640UHC-4TG144I	640	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-640UHC-5TG144I	640	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-640UHC-6TG144I	640	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	IND